


<b>Search Notes</b> 	<b>Application/Control No.</b> 10533690	<b>Applicant(s)/Patent Under Reexamination</b> CHOI ET AL.
	<b>Examiner</b> KAMRAN AFSHAR	<b>Art Unit</b> 2617

SEARCHED			
Class	Subclass	Date	Examiner
370	328, 336, 337, 347, 4522-356, 569, 401	2/19/2009	KA
455	403, 422.1, 428, 445, 560-561	2/19/2009	KA

SEARCH NOTES		
Search Notes	Date	Examiner
East Search (US-PGPUB; USPAT; USOCR: FPRS: EPO; DERWENT;IBM TDB)	2/19/2009	KA
Dwayne Bost	2/19/2009	KA

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/K. A./ Primary Examiner.Art Unit 2617
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